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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/768,119	CHIU ET AL.	
Examiner	Art Unit	_
Javaid Nasri	2839	

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INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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Including US-PGPub, USPAT, USOCR, EPO, JPO, IBM_TDB and Derwent data base.	7/21/2005	JN	
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